


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517213	<b>Applicant(s)/Patent Under Reexamination</b>  YAMANE, MITOKU
	<b>Examiner</b>  Quoc A Tran	<b>Art Unit</b>  2176

SEARCHED			
Class	Subclass	Date	Examiner
715	262, 700	3/27/2008	QT
455	90.3	3/27/2008	QT
341	28	3/27/2008	QT
345	168-169	3/27/2008	QT
704	2	3/27/2008	QT
Updated	Updated	9/29/2008	QT

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, USPGPUB, JPO, USOCR, FPRS, EPO, DERWENT & IBM_TDB)	3/27/2008	QT
Inventors Searched Conducted- Considered Double Patent Rejection	3/27/2008	QT
NPL Search (ACM Digital Library)	3/27/2008	QT
Text Search Class 715/262, 700; 455/All; 345/168-169; 704/2;	3/27/2008	QT
Updated Above	9/29/2008	QT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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